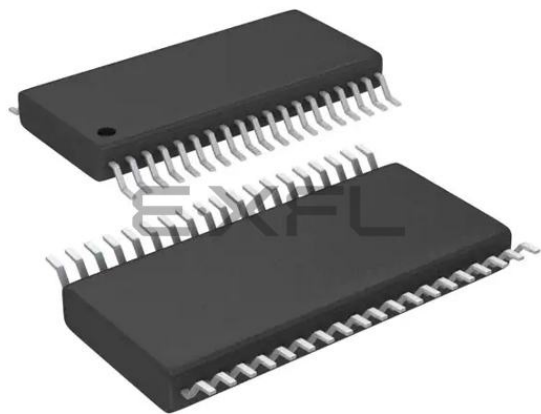




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Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I ² S, POR, PWM, WDT
Number of I/O	26
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	38-TFSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-38-9
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1201t038f0032abxuma1

On-Chip Debug Support

- Support for debug features: 4 breakpoints, 2 watchpoints
- Various interfaces: ARM serial wire debug (SWD), single pin debug (SPD)

1.1 Ordering Information

The ordering code for an Infineon microcontroller provides an exact reference to a specific product. The code "XMC1<DDD>-<Z><PPP><T><FFFF>" identifies:

- <DDD> the derivatives function set
- <Z> the package variant
 - T: TSSOP
 - Q: VQFN
- <PPP> package pin count
- <T> the temperature range:
 - F: -40°C to 85°C
 - X: -40°C to 105°C
- <FFFF> the Flash memory size.

For ordering codes for the XMC1200 please contact your sales representative or local distributor.

This document describes several derivatives of the XMC1200 series, some descriptions may not apply to a specific product. Please see [Table 1](#).

For simplicity the term **XMC1200** is used for all derivatives throughout this document.

1.2 Device Types

These device types are available and can be ordered through Infineon's direct and/or distribution channels.

Table 1 Synopsis of XMC1200 Device Types

Derivative	Package	Flash Kbytes	SRAM Kbytes
XMC1201-T028F0016	PG-TSSOP-28-16	16	16
XMC1201-T028F0032	PG-TSSOP-28-16	32	16
XMC1201-T038F0016	PG-TSSOP-38-9	16	16
XMC1201-T038F0032	PG-TSSOP-38-9	32	16
XMC1201-T038F0064	PG-TSSOP-38-9	64	16
XMC1201-T038F0128	PG-TSSOP-38-9	128	16
XMC1201-T038F0200	PG-TSSOP-38-9	200	16
XMC1200-T038F0200	PG-TSSOP-38-9	200	16

2 General Device Information

This section summarizes the logic symbols and package pin configurations with a detailed list of the functional I/O mapping.

2.1 Logic Symbols

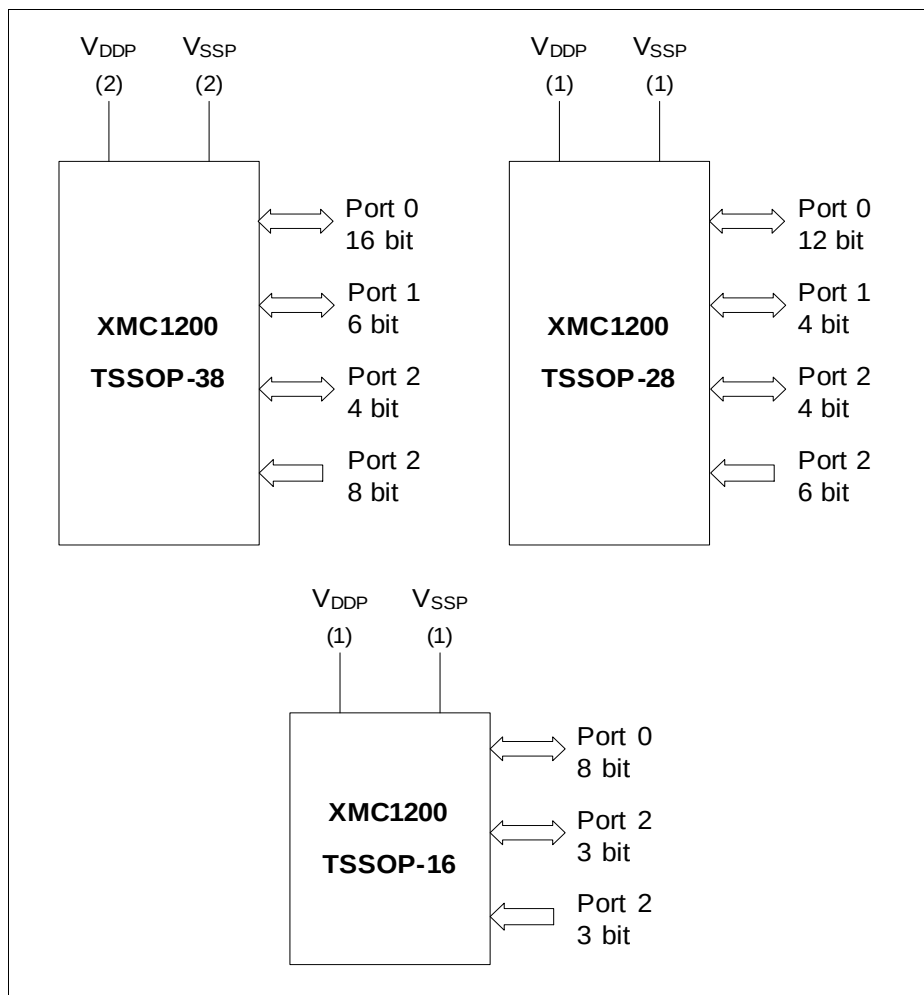


Figure 2 XMC1200 Logic Symbol for TSSOP-38, TSSOP-28 and TSSOP-16

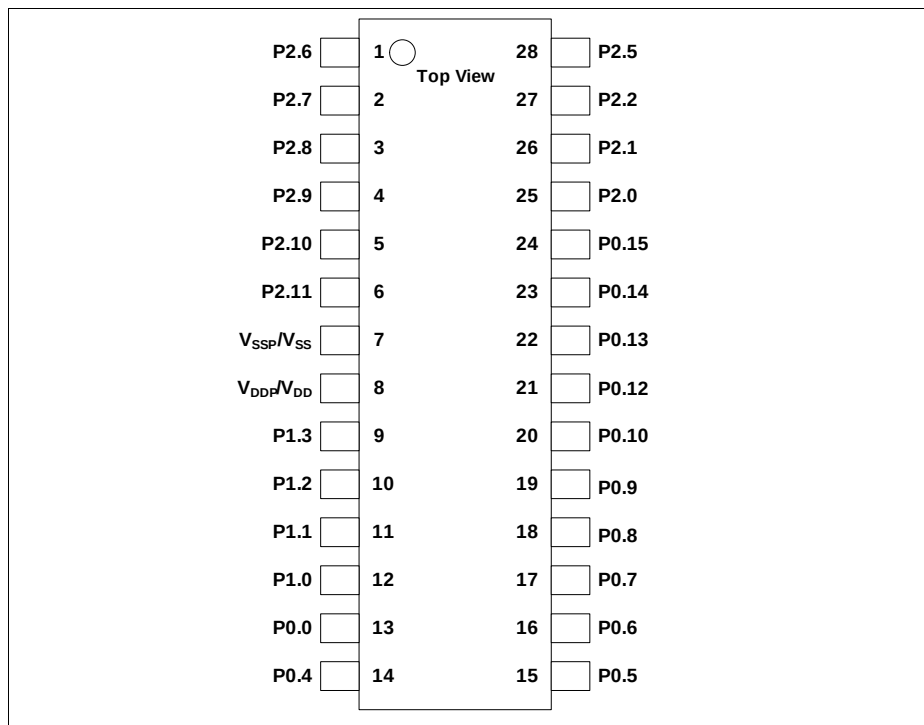


Figure 5 XMC1200 PG-TSSOP-28 Pin Configuration (top view)

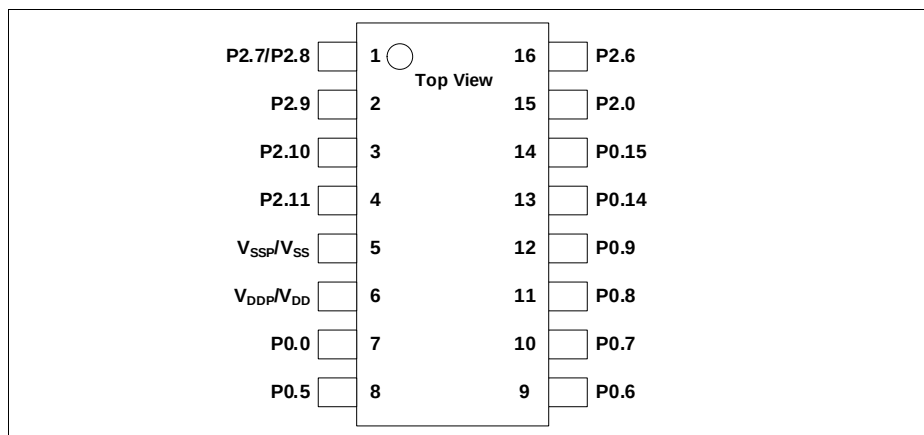


Figure 6 XMC1200 PG-TSSOP-16 Pin Configuration (top view)

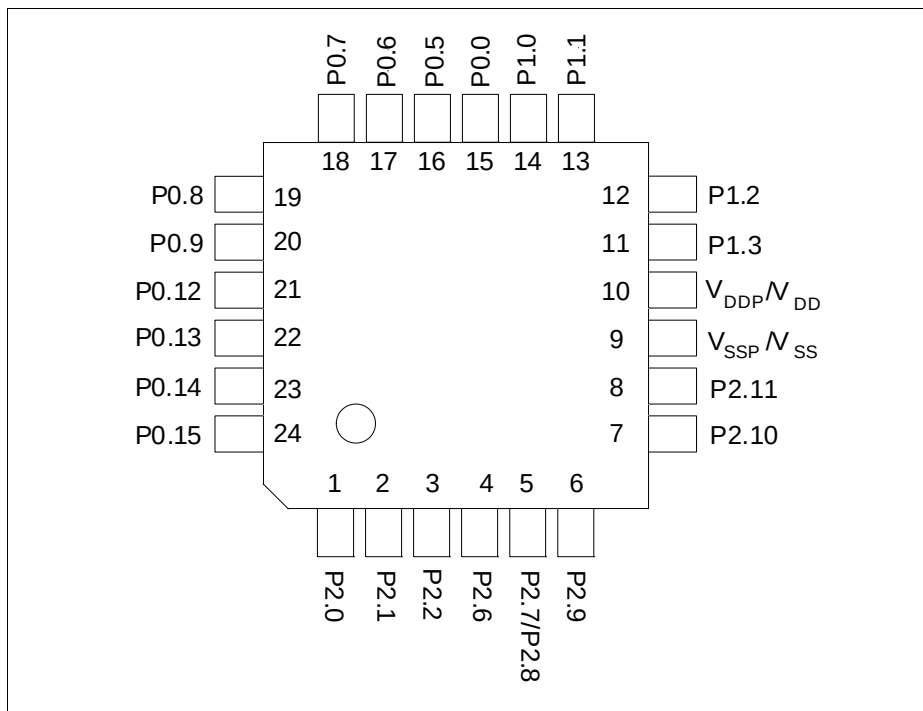


Figure 7 XMC1200 PG-VQFN-24 Pin Configuration (top view)

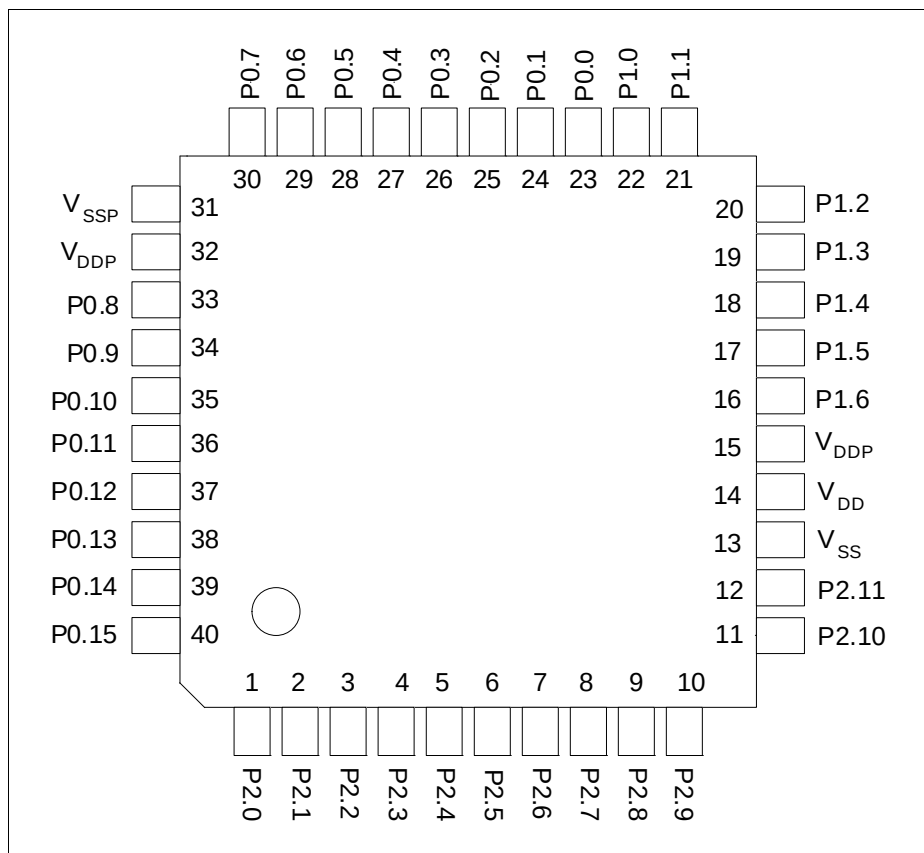


Figure 8 XMC1200 PG-VQFN-40 Pin Configuration (top view)

General Device Information

Table 6 Package Pin Mapping (cont'd)

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
VSSP	31	25	-	-	-	Power	I/O port ground
VDDP	32	26	-	-	-	Power	I/O port supply
VSSP	Exp. Pad	-	-	Exp. Pad	-	Power	Exposed Die Pad The exposed die pad is connected internally to VSSP. For proper operation, it is mandatory to connect the exposed pad to the board ground. For thermal aspects, please refer to the Package and Reliability chapter.

Table 9 Port I/O Functions

Function	Outputs							Inputs							
	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	Input	Input	Input	Input	Input	Input	Input	Input
P0.0	ERU0. P0OUT0	LEDTS0. LINE7	ERU0. GOUT0	CCU40. OUT0		USIC0_CH 0.SELO0	USIC0_CH 1.SELO0	BCCU0. TRAPINB	CCU40.IN0 C			USIC0_CH 0.DX2A	USIC0_CH 1.DX2A		
P0.1	ERU0. P0OUT1	LEDTS0. LINE6	ERU0. GOUT1	CCU40. OUT1		BCCU0. OUT8	SCU. VDROP		CCU40.IN1 C						
P0.2	ERU0. P0OUT2	LEDTS0. LINE5	ERU0. GOUT2	CCU40. OUT2		VADC0. EMUX02			CCU40.IN2 C						
P0.3	ERU0. P0OUT3	LEDTS0. LINE4	ERU0. GOUT3	CCU40. OUT3		VADC0. EMUX01			CCU40.IN3 C						
P0.4	BCCU0. OUT0	LEDTS0. LINE3	LEDTS0. COL3	CCU40. OUT1		VADC0. EMUX00	WWDT. SERVICE_ OUT								
P0.5	BCCU0. OUT1	LEDTS0. LINE2	LEDTS0. COL2	CCU40. OUT0		ACMP2. OUT									
P0.6	BCCU0. OUT2	LEDTS0. LINE1	LEDTS0. COL1	CCU40. OUT0		USIC0_CH 1.MCLKOU T	USIC0_CH 1.DOUT0		CCU40.IN0 B			USIC0_CH 1.DX0C			
P0.7	BCCU0. OUT3	LEDTS0. LINE0	LEDTS0. COL0	CCU40. OUT1		USIC0_CH 0.SCLKOU T	USIC0_CH 1.DOUT0		CCU40.IN1 B			USIC0_CH 0.DX1C	USIC0_CH 1.DX0D	USIC0_CH 1.DX1C	
P0.8	BCCU0. OUT4	LEDTS1. LINE0	LEDTS0. COLA	CCU40. OUT2		USIC0_CH 0.SCLKOU T	USIC0_CH 1.SCLKOU T		CCU40.IN2 B			USIC0_CH 0.DX1B	USIC0_CH 1.DX1B		
P0.9	BCCU0. OUT5	LEDTS1. LINE1	LEDTS0. COL6	CCU40. OUT3		USIC0_CH 0.SELO0	USIC0_CH 1.SELO0		CCU40.IN3 B			USIC0_CH 0.DX2B	USIC0_CH 1.DX2B		
P0.10	BCCU0. OUT6	LEDTS1. LINE2	LEDTS0. COL5	ACMP0. OUT		USIC0_CH 0.SELO1	USIC0_CH 1.SELO1					USIC0_CH 0.DX2C	USIC0_CH 1.DX2C		
P0.11	BCCU0. OUT7	LEDTS1. LINE3	LEDTS0. COL4	USIC0_CH 0.MCLKOU T		USIC0_CH 0.SELO2	USIC0_CH 1.SELO2					USIC0_CH 0.DX2D	USIC0_CH 1.DX2D		
P0.12	BCCU0. OUT6	LEDTS1. LINE4	LEDTS0. COL3	LEDTS1. COL3		USIC0_CH 0.SELO3		BCCU0. TRAPINA	CCU40.IN0 A	CCU40.IN1 A	CCU40.IN2 A	CCU40.IN3 A	USIC0_CH 0.DX2E		
P0.13	WWDT. SERVICE_ OUT	LEDTS1. LINE5	LEDTS0. COL2	LEDTS1. COL2		USIC0_CH 0.SELO4						USIC0_CH 0.DX2F			
P0.14	BCCU0. OUT7	LEDTS1. LINE6	LEDTS0. COL1	LEDTS1. COL1		USIC0_CH 0.DOUT0	USIC0_CH 0.SCLKOU T					USIC0_CH 0.DX0A	USIC0_CH 0.DX1A		

Table 9 Port I/O Functions

Function	Outputs							Inputs							
	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	Input	Input	Input	Input	Input	Input	Input	Input
P0.15	BCCU0. OUT8	LEDTS1. LINE7	LEDTS0. COL0	LEDTS1. COL0		USIC0_CH 0.DOUT0	USIC0_CH 1.MCLKOUT					USIC0_CH 0.DX0B			
P1.0	BCCU0. OUT0	CCU40. OUT0	LEDTS0. COL0	LEDTS1. COLA		ACMP1. OUT	USIC0_CH 0.DOUT0					USIC0_CH 0.DX0C			
P1.1	VADC0. EMUX00	CCU40. OUT1	LEDTS0. COL1	LEDTS1. COL0		USIC0_CH 0.DOUT0	USIC0_CH 1.SELO0					USIC0_CH 0.DX0D	USIC0_CH 0.DX1D	USIC0_CH 1.DX2E	
P1.2	VADC0. EMUX01	CCU40. OUT2	LEDTS0. COL2	LEDTS1. COL1		ACMP2. OUT	USIC0_CH 1.DOUT0					USIC0_CH 1.DX0B			
P1.3	VADC0. EMUX02	CCU40. OUT3	LEDTS0. COL3	LEDTS1. COL2		USIC0_CH 1.SCLKOUT	USIC0_CH 1.DOUT0					USIC0_CH 1.DX0A	USIC0_CH 1.DX1A		
P1.4	VADC0. EMUX10	USIC0_CH 1.SCLKOUT	LEDTS0. COL4	LEDTS1. COL3		USIC0_CH 0.SELO0	USIC0_CH 1.SELO1					USIC0_CH 0.DX5E	USIC0_CH 1.DX5E		
P1.5	VADC0. EMUX11	USIC0_CH 0.DOUT0	LEDTS0. COLA	BCCU0. OUT1		USIC0_CH 0.SELO1	USIC0_CH 1.SELO2					USIC0_CH 1.DX5F			
P1.6	VADC0. EMUX12	USIC0_CH 1.DOUT0	LEDTS0. COL5	USIC0_CH 0.SCLKOUT	BCCU0. OUT2	USIC0_CH 0.SELO2	USIC0_CH 1.SELO3			USIC0_CH 0.DX5F					
P2.0	ERU0. PDUOT3	CCU40. OUT0	ERU0. GOUT3	LEDTS1. COL5		USIC0_CH 0.DOUT0	USIC0_CH 0.SCLKOUT		VADC0. G0CH5		ERU0.0B0	USIC0_CH 0.DX0E	USIC0_CH 0.DX1E	USIC0_CH 1.DX2F	
P2.1	ERU0. PDUOT2	CCU40. OUT1	ERU0. GOUT2	LEDTS1. COL6		USIC0_CH 0.DOUT0	USIC0_CH 1.SCLKOUT	ACMP2.INP	VADC0. G0CH6		ERU0.1B0	USIC0_CH 0.DX0F	USIC0_CH 1.DX3A	USIC0_CH 1.DX4A	
P2.2								ACMP2.INN	VADC0. G0CH7		ERU0.0B1	USIC0_CH 0.DX3A	USIC0_CH 0.DX4A	USIC0_CH 1.DX5A	ORC0.AIN
P2.3									VADC0. G1CH5		ERU0.1B1	USIC0_CH 0.DX5B	USIC0_CH 1.DX3C	USIC0_CH 1.DX4C	ORC1.AIN
P2.4									VADC0. G1CH6		ERU0.0A1	USIC0_CH 0.DX3B	USIC0_CH 0.DX4B	USIC0_CH 1.DX5B	ORC2.AIN
P2.5									VADC0. G1CH7		ERU0.1A1	USIC0_CH 0.DX5D	USIC0_CH 1.DX3E	USIC0_CH 1.DX4E	ORC3.AIN
P2.6								ACMP1.INN	VADC0. G0CH0		ERU0.2A1	USIC0_CH 0.DX3E	USIC0_CH 0.DX4E	USIC0_CH 1.DX5D	ORC4.AIN
P2.7								ACMP1.INP	VADC0. G1CH1		ERU0.3A1	USIC0_CH 0.DX5C	USIC0_CH 1.DX3D	USIC0_CH 1.DX4D	ORC5.AIN

Table 10 Hardware Controlled I/O Functions

Function	Outputs		Inputs		Pull Control			
	HWO0	HWO1	HWI0	HWI1	HW0_PD	HW0_PU	HW1_PD	HW1_PU
P0.0	LEDTS0. EXTENDED7		LEDTS0.TSIN7	LEDTS0. TSIN7	Reserved for LEDTS Scheme A: pull-down disabled always	Reserved for LEDTS Scheme A: pull-down enabled always	Reserved for LEDTS Scheme B: pull-up enabled and pull-down disabled, and vice versa	
P0.1	LEDTS0. EXTENDED6		LEDTS0.TSIN6	LEDTS0. TSIN6				
P0.2	LEDTS0. EXTENDED5		LEDTS0.TSIN5	LEDTS0. TSIN5				
P0.3	LEDTS0. EXTENDED4		LEDTS0.TSIN4	LEDTS0. TSIN4				
P0.4	LEDTS0. EXTENDED3		LEDTS0. TSIN3	LEDTS0. TSIN3				
P0.5	LEDTS0. EXTENDED2		LEDTS0. TSIN2	LEDTS0. TSIN2				
P0.6	LEDTS0. EXTENDED1		LEDTS0. TSIN1	LEDTS0. TSIN1				
P0.7	LEDTS0. EXTENDED0		LEDTS0. TSIN0	LEDTS0. TSIN0				
P0.8	LEDTS1. EXTENDED0		LEDTS1. TSIN0	LEDTS1. TSIN0				
P0.9	LEDTS1. EXTENDED1		LEDTS1. TSIN1	LEDTS1. TSIN1				
P0.10	LEDTS1. EXTENDED2		LEDTS1. TSIN2	LEDTS1. TSIN2				
P0.11	LEDTS1. EXTENDED3		LEDTS1. TSIN3	LEDTS1. TSIN3				
P0.12	LEDTS1. EXTENDED4		LEDTS1. TSIN4	LEDTS1. TSIN4				
P0.13	LEDTS1. EXTENDED5		LEDTS1. TSIN5	LEDTS1. TSIN5				
P0.14	LEDTS1. EXTENDED6		LEDTS1. TSIN6	LEDTS1. TSIN6				
P0.15	LEDTS1. EXTENDED7		LEDTS1. TSIN7	LEDTS1. TSIN7				
P1.0		USIC0_CH0.DOUT0		USIC0_CH0.HWIN0	BCCU0.OUT2	BCCU0.OUT2		
P1.1		USIC0_CH0.DOUT1		USIC0_CH0.HWIN1	BCCU0.OUT3	BCCU0.OUT3		
P1.2		USIC0_CH0.DOUT2		USIC0_CH0.HWIN2	BCCU0.OUT4	BCCU0.OUT4		

Table 16 Input/Output Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Pin capacitance (digital inputs/outputs)	C_{IO}	CC	–	10	pF	
Pull-up resistor on port pins	R_{PUP}	CC	20	50	kohm	$V_{IN} = V_{SSP}$
Pull-down resistor on port pins	R_{PDP}	CC	20	50	kohm	$V_{IN} = V_{DDP}$
Input leakage current ⁹⁾	I_{OZP}	CC	-1	1	μA	$0 < V_{IN} < V_{DDP}$, $T_A \leq 105\text{ °C}$
Voltage on any pin during V_{DDP} power off	V_{PO}	SR	–	0.3	V	¹⁰⁾
Maximum current per pin (excluding P1, V_{DDP} and V_{SS})	I_{MP}	SR	-10	11	mA	–
Maximum current per high current pins	I_{MP1A}	SR	-10	50	mA	–
Maximum current into V_{DDP} (TSSOP28/16, VQFN24)	I_{MVDD1}	SR	–	130	mA	¹⁰⁾
Maximum current into V_{DDP} (TSSOP38, VQFN40)	I_{MVDD2}	SR	–	260	mA	¹⁰⁾
Maximum current out of V_{SS} (TSSOP28/16, VQFN24)	I_{MVSS1}	SR	–	130	mA	¹⁰⁾
Maximum current out of V_{SS} (TSSOP38, VQFN40)	I_{MVSS2}	SR	–	260	mA	¹⁰⁾

1) Rise/Fall time parameters are taken with 10% - 90% of supply.

2) Additional rise/fall time valid for $C_L = 50\text{ pF}$ - $C_L = 100\text{ pF}$ @ 0.150 ns/pF at 5 V supply voltage.

3) Additional rise/fall time valid for $C_L = 50\text{ pF}$ - $C_L = 100\text{ pF}$ @ 0.205 ns/pF at 3.3 V supply voltage.

4) Additional rise/fall time valid for $C_L = 50\text{ pF}$ - $C_L = 100\text{ pF}$ @ 0.445 ns/pF at 1.8 V supply voltage.

5) Additional rise/fall time valid for $C_L = 50\text{ pF}$ - $C_L = 100\text{ pF}$ @ 0.225 ns/pF at 5 V supply voltage.

6) Additional rise/fall time valid for $C_L = 50\text{ pF}$ - $C_L = 100\text{ pF}$ @ 0.288 ns/pF at 3.3 V supply voltage.

7) Additional rise/fall time valid for $C_L = 50\text{ pF}$ - $C_L = 100\text{ pF}$ @ 0.588 ns/pF at 1.8 V supply voltage.

Electrical Parameter
Table 17 ADC Characteristics (Operating Conditions apply)¹⁾ (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gain settings	G_{IN} CC	1			–	GNCTRxz.GAINy = 00 _B (unity gain)
		3			–	GNCTRxz.GAINy = 01 _B (gain g1)
		6			–	GNCTRxz.GAINy = 10 _B (gain g2)
		12			–	GNCTRxz.GAINy = 11 _B (gain g3)
Sample Time	t_{sample} CC	3	–	–	1 / f_{ADC}	$V_{DD} = 5.0$ V
		3	–	–	1 / f_{ADC}	$V_{DD} = 3.3$ V
		30	–	–	1 / f_{ADC}	$V_{DD} = 2.0$ V
Sigma delta loop hold time	t_{SD_hold} CC	20	–	–	μs	Residual charge stored in an active sigma delta loop remains available
Conversion time in fast compare mode	t_{CF} CC	9			1 / f_{ADC}	²⁾
Conversion time in 12-bit mode	t_{C12} CC	20			1 / f_{ADC}	²⁾
Maximum sample rate in 12-bit mode ³⁾	f_{C12} CC	–	–	$f_{ADC} / 42.5$	–	1 sample pending
		–	–	$f_{ADC} / 62.5$	–	2 samples pending
Conversion time in 10-bit mode	t_{C10} CC	18			1 / f_{ADC}	²⁾
Maximum sample rate in 10-bit mode ³⁾	f_{C10} CC	–	–	$f_{ADC} / 40.5$	–	1 sample pending
		–	–	$f_{ADC} / 58.5$	–	2 samples pending
Conversion time in 8-bit mode	t_{C8} CC	16			1 / f_{ADC}	²⁾

3.2.5 Temperature Sensor Characteristics

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 20 Temperature Sensor Characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Measurement time	t_M CC	–	–	10	ms	
Temperature sensor range	T_{SR} SR	-40	–	115	°C	
Sensor Accuracy ¹⁾	T_{TSAL} CC	-6	–	6	°C	$T_J > 20^\circ\text{C}$
		-10	–	10	°C	$0^\circ\text{C} \leq T_J \leq 20^\circ\text{C}$
		-18	–	18	°C	$-25^\circ\text{C} \leq T_J < 0^\circ\text{C}$
		-31	–	31	°C	$-40^\circ\text{C} \leq T_J < -25^\circ\text{C}$
Start-up time after enabling	t_{TSSTE} SR	–	–	15	µs	

1) The temperature sensor accuracy is independent of the supply voltage.

Table 21 Power Supply Parameters; $V_{DDP} = 5V$

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min	Typ. ¹⁾	Max.		
Sleep mode current Peripherals clock disabled Flash active f_{MCLK} / f_{PCLK} in MHz ⁵⁾	I_{DDPSD} CC	–	1.8	–	mA	32 / 64
			1.7	–	mA	24 / 48
			1.6	–	mA	16 / 32
			1.5	–	mA	8 / 16
			1.4	–	mA	1 / 1
Sleep mode current Peripherals clock disabled Flash powered down f_{MCLK} / f_{PCLK} in MHz ⁶⁾	I_{DDPSR} CC	–	1.2	–	mA	32 / 64
			1.1	–	mA	24 / 48
			1.0	–	mA	16 / 32
			0.8	–	mA	8 / 16
			0.7	–	mA	1 / 1
Deep Sleep mode current ⁷⁾	I_{DDPDS} CC	–	0.24	–	mA	
Wake-up time from Sleep to Active mode ⁸⁾	t_{SSA} CC	–	6	–	cycles	
Wake-up time from Deep Sleep to Active mode ⁹⁾	t_{DSA} CC	–	280	–	μsec	

1) The typical values are measured at $T_A = +25\text{ °C}$ and $V_{DDP} = 5V$.

2) CPU and all peripherals clock enabled, Flash is in active mode.

3) CPU enabled, all peripherals clock disabled, Flash is in active mode.

4) CPU in sleep, all peripherals clock enabled and Flash is in active mode.

5) CPU in sleep, Flash is in active mode.

6) CPU in sleep, Flash is powered down and code executed from RAM after wake-up.

7) CPU in sleep, peripherals clock disabled, Flash is powered down and code executed from RAM after wake-up.

8) CPU in sleep, Flash is in active mode during sleep mode.

9) CPU in sleep, Flash is in powered down mode during deep sleep mode.

Table 24 Power-Up and Supply Monitoring Parameters (Operating Conditions apply)¹⁾ (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
V_{DDP} brownout reset voltage	V_{DDPBO} CC	1.55	1.62	1.75	V	calibrated, before user code starts running
V_{DDP} voltage to ensure defined pad states	V_{DDPPA} CC	–	1.0	–	V	
Start-up time from power-on reset	t_{SSW} SR	–	320	–	μs	Time to the first user code instruction in all start-up modes ⁴⁾
BMI program time	t_{BMI} SR	–	8.25	–	ms	Time taken from a user-triggered system reset after BMI installation is requested

- 1) Not all parameters are 100% tested, but are verified by design/characterisation.
- 2) A capacitor of at least 100 nF has to be added between V_{DDP} and V_{SSP} to fulfill the requirement as stated for this parameter.
- 3) Valid for a 100 nF buffer capacitor connected to supply pin where current from capacitor is forwarded only to the chip. A larger capacitor value has to be chosen if the power source sink a current.
- 4) This values does not include the ramp-up time. During startup firmware execution, MCLK is running at 32 MHz and the clocks to peripheral as specified in register CGATSTAT0 are gated.

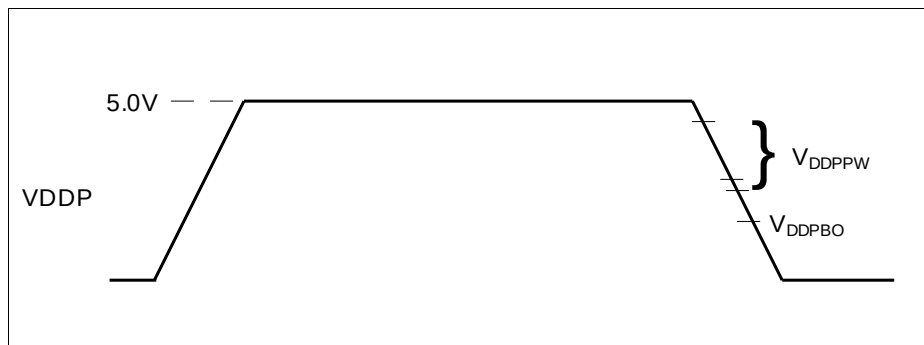


Figure 19 Supply Threshold Parameters

3.3.3 On-Chip Oscillator Characteristics

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 25 provides the characteristics of the 64 MHz clock output from the digital controlled oscillator, DCO1 in XMC1200.

Table 25 64 MHz DCO1 Characteristics (Operating Conditions apply)

Parameter	Symbol	Limit Values			Unit	Test Conditions
		Min.	Typ.	Max.		
Nominal frequency	f_{NOM} CC	–	64	–	MHz	under nominal conditions ¹⁾ after trimming
Accuracy ²⁾	Δf_{LT} CC	-1.7	–	3.4	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature (0 °C to 85 °C)
		-3.9	–	4.0	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature (-40 °C to 105 °C)

1) The deviation is relative to the factory trimmed frequency at nominal V_{DDC} and $T_{\text{A}} = + 25\text{ °C}$.

2) The accuracy of the DCO1 oscillator can be further improved through alternative methods, refer to XMC1000 Oscillator Handling Application Note.

Table 32 USIC IIC Fast Mode Timing¹⁾

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	20 + 0.1* C_b 2)	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	20 + 0.1* C_b	-	300	ns	
Data hold time	t_3 CC/SR	0	-	-	µs	
Data set-up time	t_4 CC/SR	100	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	1.3	-	-	µs	
HIGH period of SCL clock	t_6 CC/SR	0.6	-	-	µs	
Hold time for (repeated) START condition	t_7 CC/SR	0.6	-	-	µs	
Set-up time for repeated START condition	t_8 CC/SR	0.6	-	-	µs	
Set-up time for STOP condition	t_9 CC/SR	0.6	-	-	µs	
Bus free time between a STOP and START condition	t_{10} CC/SR	1.3	-	-	µs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximately 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

2) C_b refers to the total capacitance of one bus line in pF.

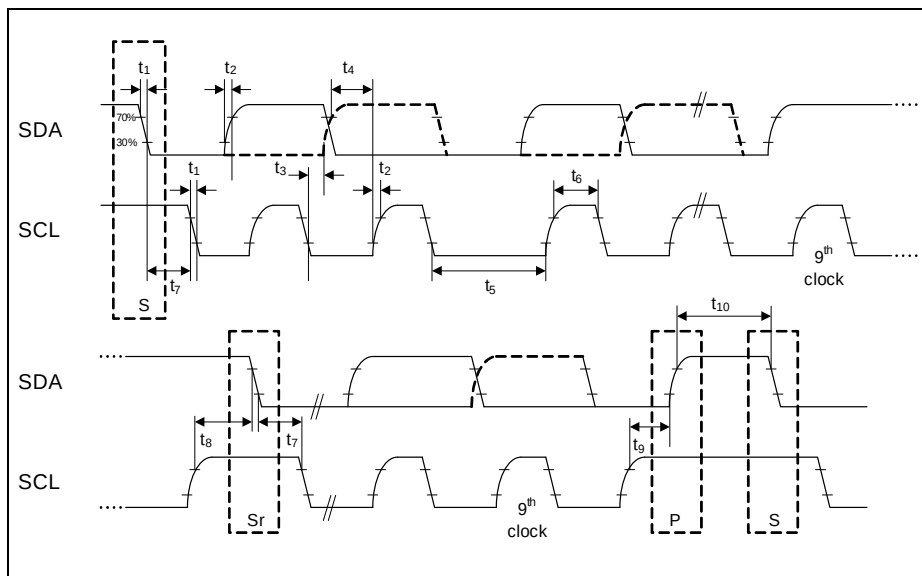


Figure 23 USIC IIC Stand and Fast Mode Timing

3.3.6.3 Inter-IC Sound (IIS) Interface Timing

The following parameters are applicable for a USIC channel operated in IIS mode.

Note: Operating Conditions apply.

Table 33 USIC IIS Master Transmitter Timing

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Clock period	t_1 CC	$2/f_{MCLK}$	-	-	ns	$V_{DDP} \geq 3\text{ V}$
		$4/f_{MCLK}$	-	-	ns	$V_{DDP} < 3\text{ V}$
Clock HIGH	t_2 CC	$0.35 \times t_{1min}$	-	-	ns	
Clock Low	t_3 CC	$0.35 \times t_{1min}$	-	-	ns	
Hold time	t_4 CC	0	-	-	ns	
Clock rise time	t_5 CC	-	-	$0.15 \times t_{1min}$	ns	

Package and Reliability

The difference between junction temperature and ambient temperature is determined by

$$\Delta T = (P_{\text{INT}} + P_{\text{IOSTAT}} + P_{\text{IODYN}}) \times R_{\Theta JA}$$

The internal power consumption is defined as

$$P_{\text{INT}} = V_{\text{DDP}} \times I_{\text{DDP}} \text{ (switching current and leakage current).}$$

The static external power consumption caused by the output drivers is defined as

$$P_{\text{IOSTAT}} = \Sigma((V_{\text{DDP}} - V_{\text{OH}}) \times I_{\text{OH}}) + \Sigma(V_{\text{OL}} \times I_{\text{OL}})$$

The dynamic external power consumption caused by the output drivers (P_{IODYN}) depends on the capacitive load connected to the respective pins and their switching frequencies.

If the total power dissipation for a given system configuration exceeds the defined limit, countermeasures must be taken to ensure proper system operation:

- Reduce V_{DDP} , if possible in the system
- Reduce the system frequency
- Reduce the number of output pins
- Reduce the load on active output drivers

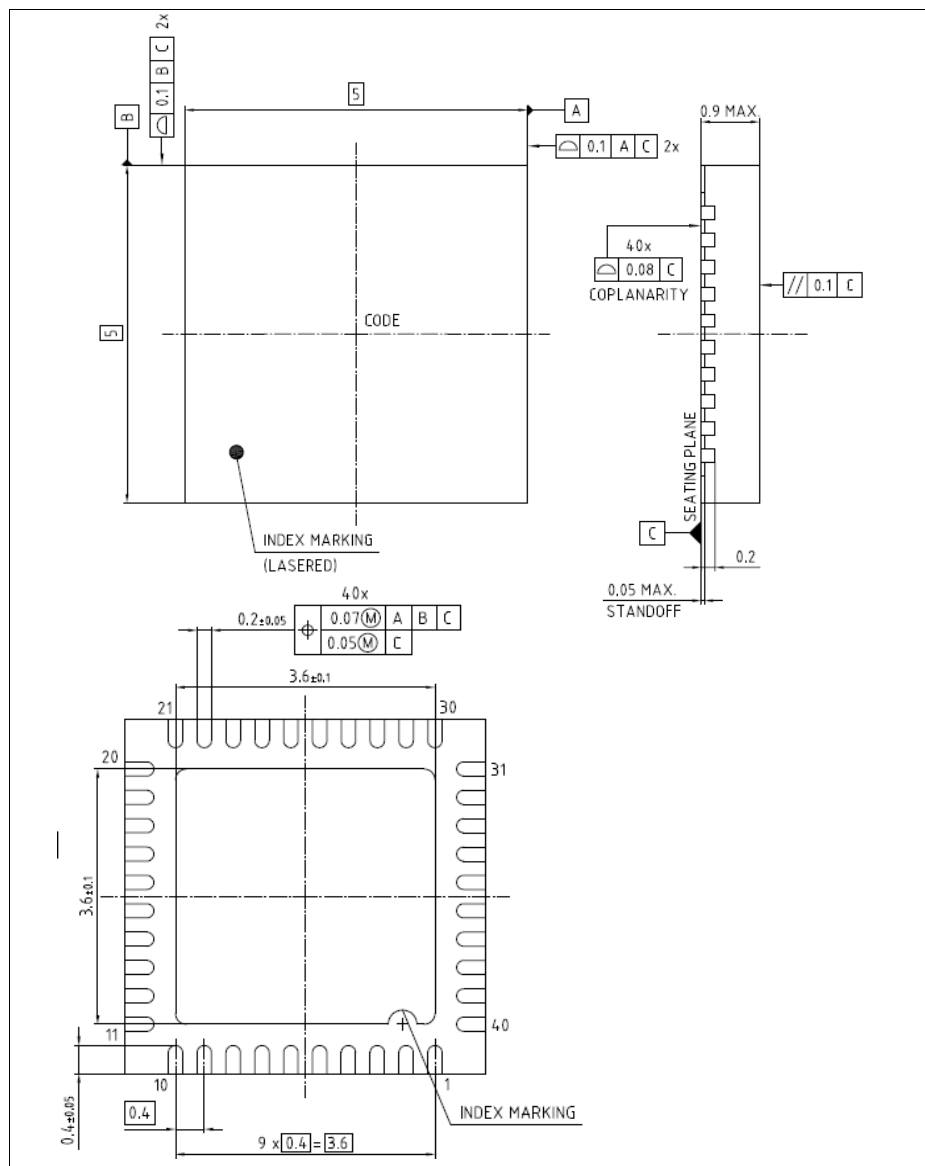


Figure 30 PG-VQFN-40-13

All dimensions in mm.